



Supply Voltage	$V_{CC}$	-0.5 to 6.5	V
DC Input Diode Current $V_I = -0.5\text{ V}$ $V_I = V_{CC} + 0.5\text{ V}$	$I_{IK}$	-20 +20	mA
DC Input Voltage	$V_I$	-0.5 to $V_{CC} + 0.5$	V
DC Output Diode Current $V_O = -0.5\text{ V}$ $V_O = V_{CC} + 0.5\text{ V}$	$I_{OK}$	-20 +20	mA
DC Output Voltage	$V_O$	-0.5 to $V_{CC} + 0.5$	V
DC Output Source or Sink Current	$I_O$	$\pm 50$	mA
DC $V_{CC}$ or Ground Current per Output Pin	$I_{CC}$ or $I_{GND}$	$\pm 50$	mA
Storage Temperature	$T_{STG}$	-65 to +150	$^{\circ}\text{C}$

			°		- ° °			
$V_{IH}$	Minimum High Level Input Voltage	3.0	1.5	2.1	2.1	V	$V_{OUT} = 0.1\text{ V}$ or $V_{CC} - 0.1\text{ V}$	
		4.5	2.25	3.15	3.15			
		5.5	2.75	3.85	3.85			
$V_{IL}$	Maximum Low Level Input Voltage	3.0	1.5	0.9	0.9	V	$V_{OUT} = 0.1\text{ V}$ or $V_{CC} - 0.1\text{ V}$	
		4.5	2.25	1.35	1.35			
		5.5	2.75	1.65	1.65			
$V_{OH}$	Minimum High Level Output Voltage	3.0	2.99	2.9	2.9	V	$I_{OUT} = -50\text{ }\mu\text{A}$	
		4.5	4.49	4.4	4.4			
		5.5	5.49	5.4	5.4			
		3.0	-	2.56	2.46	V	$V_{IN} = V_{IL}$ or $V_{IH}$ $I_{OH} = -12\text{ mA}$ $I_{OH} = -24\text{ mA}$ $I_{OH} = -24\text{ mA}$ (Note 1)	
		4.5	-	3.86	3.76			
		5.5	-	4.86	4.76			
$V_{OL}$	Maximum Low Level Output Voltage	3.0	0.002	0.1	0.1	V	$I_{OUT} = 50\text{ }\mu\text{A}$	
		4.5	0.001	0.1	0.1			
		5.5	0.001	0.1	0.1			
		3.0	-	0.36	0.44	V	$V_{IN} = V_{IL}$ or $V_{IH}$ $I_{OL} = 12\text{ mA}$ $I_{OL} = 24\text{ mA}$ $I_{OL} = 24\text{ mA}$ (Note 1)	
		4.5	-	0.36	0.44			
		5.5	-	0.36	0.44			
$I_{IN}$ (Note 3)	Maximum Input Leakage Current	5.5	-	$\pm 0.1$	$\pm 1.0$	$\mu\text{A}$	$V_I = V_{CC}, \text{ GND}$	
$I_{OZ}$	Maximum 3-State Current	5.5	-	$\pm 0.25$	$\pm 2.5$	$\mu\text{A}$	$V_I (\text{OE}) = V_{IL}, V_{IH}$ $V_I = V_{CC}, \text{ GND}$ $V_O = V_{CC}, \text{ GND}$	
$I_{OLD}$	Minimum Dynamic Output Current (Note 2)	5.5	-	-	75	mA	$V_{OLD} = 1.65\text{ V Max}$	
$I_{OHD}$		5.5	-	-	-75	mA	$V_{OHD} = 3.85\text{ V Min}$	
$I_{CC}$ (Note 3)	Maximum Quiescent Supply Current	5.5	-	8.0	80	$\mu\text{A}$	$V_{IN} = V_{CC}$ or GND	

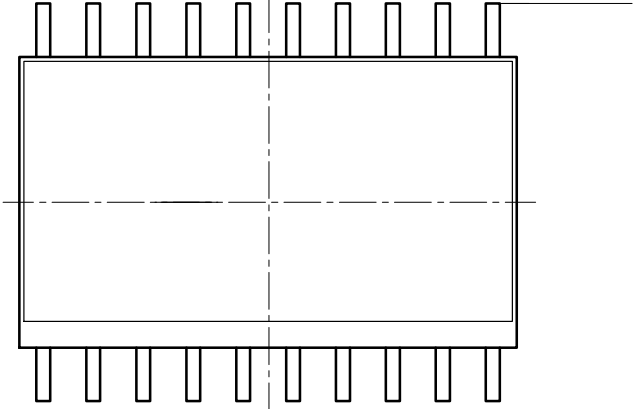
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

1. All outputs loaded; thresholds on input associated with output under test.
2. Maximum test duration 2.0 ms, one output loaded at a time.
3. I



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CASE 751BJ  
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